

N-Channel Enhancement Mode Power MOSFET

Description

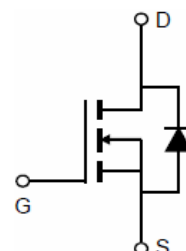
The HM4N10PR uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of applications.

General Features

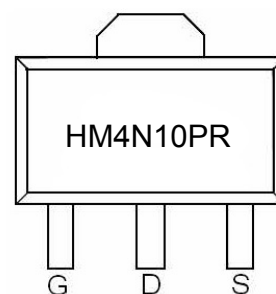
- $V_{DS} = 100V, I_D = 4A$
 $R_{DS(ON)} < 160m\Omega @ V_{GS}=10V$ (Typ:136m Ω)
 $R_{DS(ON)} < 170m\Omega @ V_{GS}=4.5V$ (Typ:140m Ω)
- High density cell design for ultra low $R_{DS(ON)}$
- Fully characterized avalanche voltage and current
- Excellent package for good heat dissipation

Application

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply



Schematic diagram



SOT-89 -3L top view

Package Marking and Ordering Information

| Device Marking | Device | Device Package | Reel Size | Tape width | Quantity |
|----------------|-----------|----------------|-----------|------------|------------|
| HM4N10PR | NHM4N10PR | SOT-89-3L | Ø330mm | 12mm | 2500 units |

Absolute Maximum Ratings ($T_A=25^\circ\text{C}$ unless otherwise noted)

| Parameter | Symbol | Limit | Unit |
|--|----------------|------------|------------------|
| Drain-Source Voltage | V_{DS} | 100 | V |
| Gate-Source Voltage | V_{GS} | ± 20 | V |
| Drain Current-Continuous | I_D | 4 | A |
| Drain Current-Pulsed ^(Note 1) | I_{DM} | 20 | A |
| Maximum Power Dissipation | P_D | 1.5 | W |
| Operating Junction and Storage Temperature Range | T_J, T_{STG} | -55 To 175 | $^\circ\text{C}$ |

Thermal Characteristic

| | | | |
|---|-----------------|-----|--------------------|
| Thermal Resistance, Junction-to-Ambient ^(Note 2) | $R_{\theta JA}$ | 100 | $^\circ\text{C/W}$ |
|---|-----------------|-----|--------------------|

Electrical Characteristics ($T_A=25^\circ\text{C}$ unless otherwise noted)

| Parameter | Symbol | Condition | Min | Typ | Max | Unit |
|---------------------------------|------------|---------------------------|-----|-----|-----|---------|
| Off Characteristics | | | | | | |
| Drain-Source Breakdown Voltage | BV_{DSS} | $V_{GS}=0V, I_D=250\mu A$ | 100 | - | - | V |
| Zero Gate Voltage Drain Current | I_{DSS} | $V_{DS}=100V, V_{GS}=0V$ | - | - | 1 | μA |

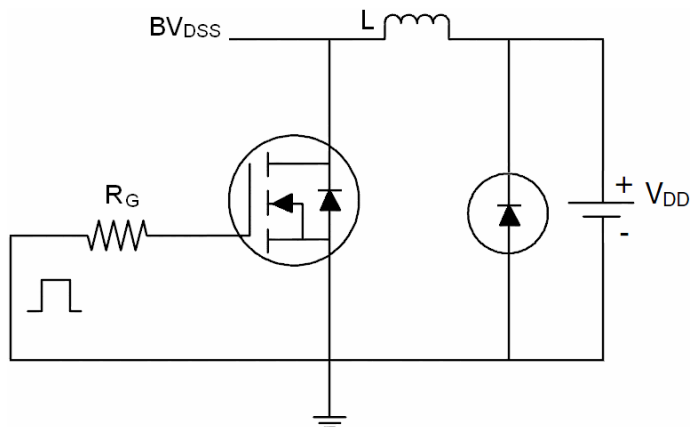
| Parameter | Symbol | Condition | Min | Typ | Max | Unit |
|------------------------------------|---------------------|--|-----|-----|------|------|
| Gate-Body Leakage Current | I _{GSS} | V _{GS} =±20V,V _{DS} =0V | - | - | ±100 | nA |
| On Characteristics (Note 3) | | | | | | |
| Gate Threshold Voltage | V _{GS(th)} | V _{DS} =V _{GS} ,I _D =250μA | 1.0 | 1.5 | 2.0 | V |
| Drain-Source On-State Resistance | R _{DS(ON)} | V _{GS} =10V, I _D =4A | - | 136 | 160 | mΩ |
| | | V _{GS} =4.5V, I _D =4A | - | 140 | 170 | |
| Forward Transconductance | g _{FS} | V _{DS} =5V,I _D =4A | - | 5 | - | S |
| Dynamic Characteristics (Note4) | | | | | | |
| Input Capacitance | C _{iss} | V _{DS} =50V,V _{GS} =0V, F=1.0MHz | - | 650 | - | PF |
| Output Capacitance | C _{oss} | | - | 24 | - | PF |
| Reverse Transfer Capacitance | C _{rss} | | - | 20 | - | PF |
| Switching Characteristics (Note 4) | | | | | | |
| Turn-on Delay Time | t _{d(on)} | V _{DD} =50V, R _L =19Ω V _{GS} =10V,R _G =3Ω | - | 6 | - | nS |
| Turn-on Rise Time | t _r | | - | 4 | - | nS |
| Turn-Off Delay Time | t _{d(off)} | | - | 20 | - | nS |
| Turn-Off Fall Time | t _f | | - | 4 | - | nS |
| Total Gate Charge | Q _g | V _{DS} =50V,I _D =4A, V _{GS} =10V | - | 20 | | nC |
| Gate-Source Charge | Q _{gs} | | - | 2.1 | - | nC |
| Gate-Drain Charge | Q _{gd} | | - | 3.3 | - | nC |
| Drain-Source Diode Characteristics | | | | | | |
| Diode Forward Voltage (Note 3) | V _{SD} | V _{GS} =0V,I _S =4A | - | - | 1.2 | V |
| Diode Forward Current (Note 2) | I _S | | - | - | 3 | A |

Notes:

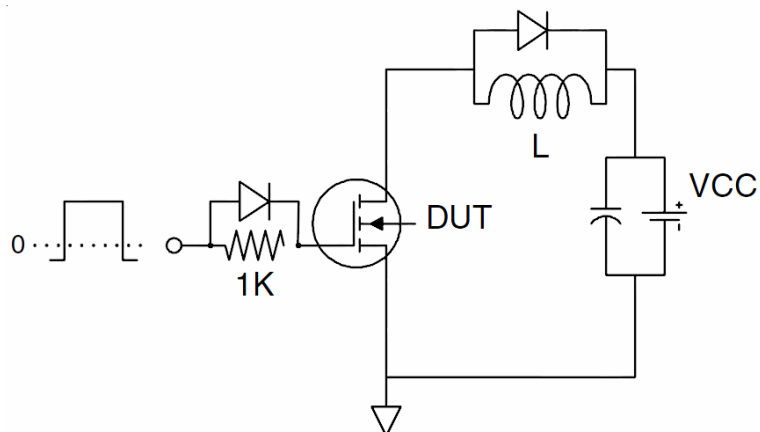
1. Repetitive Rating: Pulse width limited by maximum junction temperature.
2. Surface Mounted on FR4 Board, $t \leq 10$ sec.
3. Pulse Test: Pulse Width $\leq 300\mu s$, Duty Cycle $\leq 2\%$.
4. Guaranteed by design, not subject to production

Test Circuit

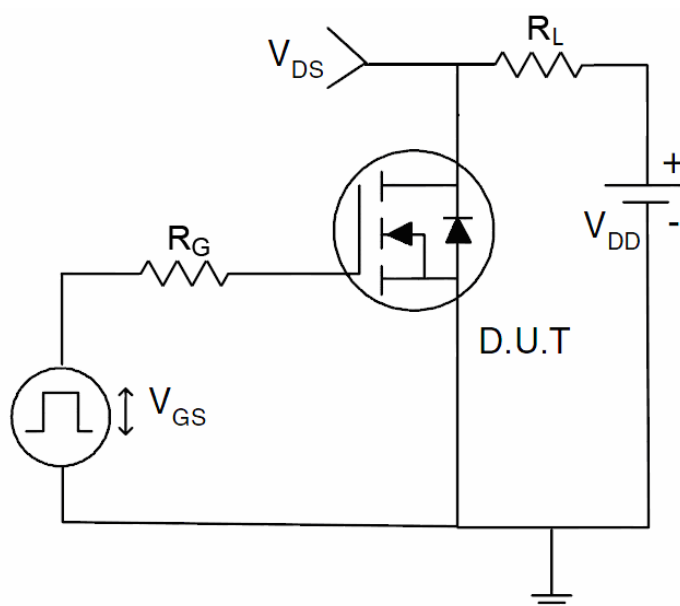
1) E_{AS} test circuit



2) Gate charge test circuit



3) Switch Time Test Circuit



Typical Electrical and Thermal Characteristics (Curves)

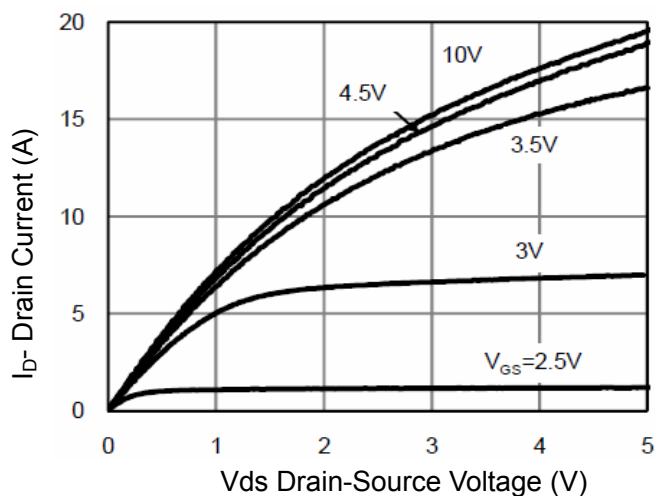


Figure 1 Output Characteristics

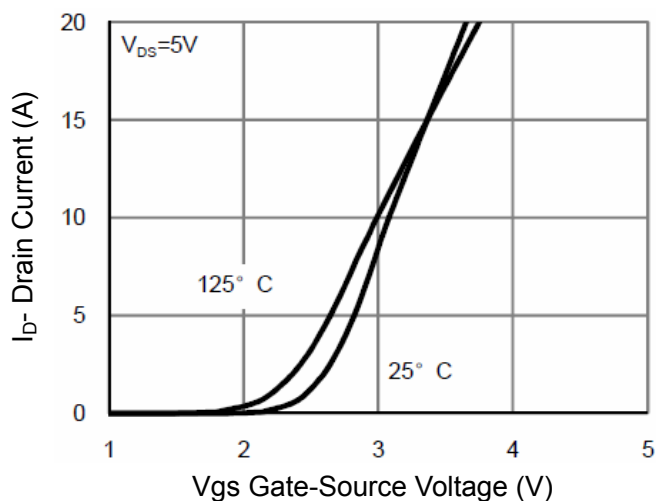


Figure 2 Transfer Characteristics

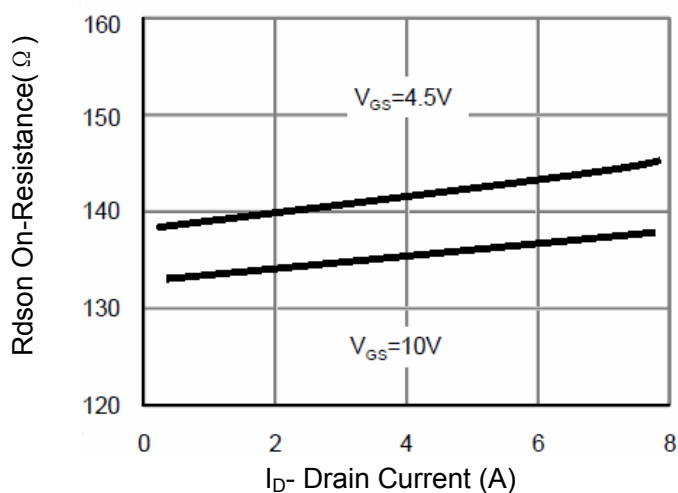


Figure 3 Rdson- Drain Current

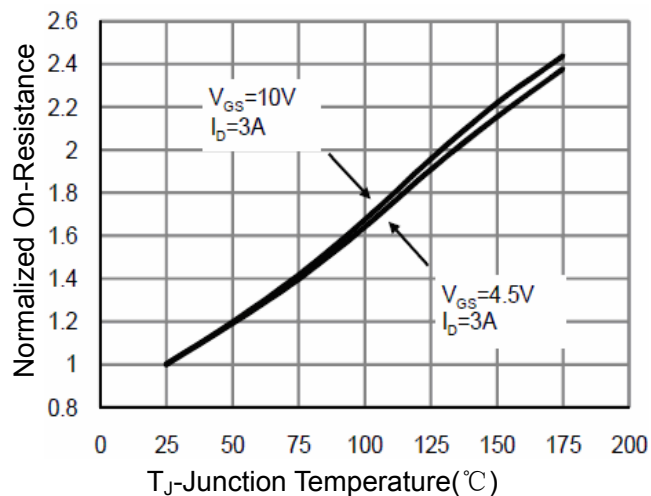


Figure 4 Rdson-Junction Temperature

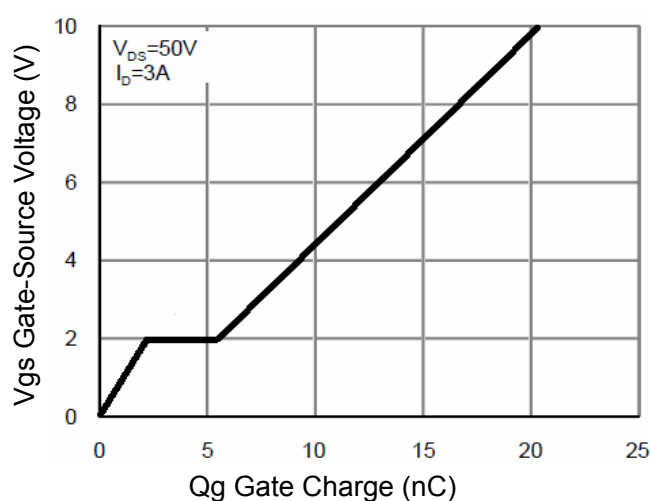


Figure 5 Gate Charge

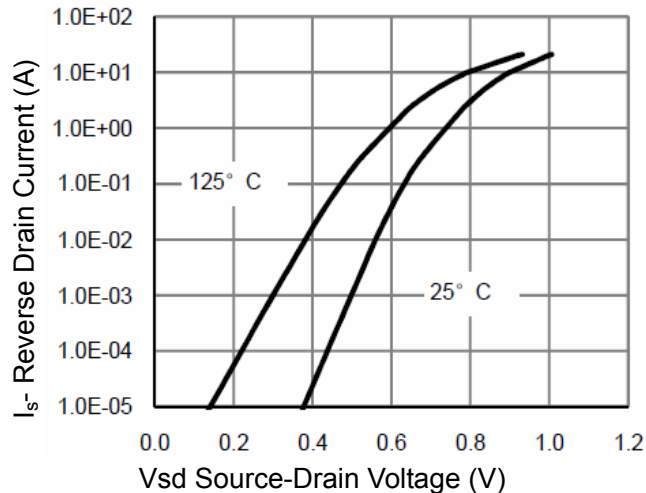


Figure 6 Source- Drain Diode Forward

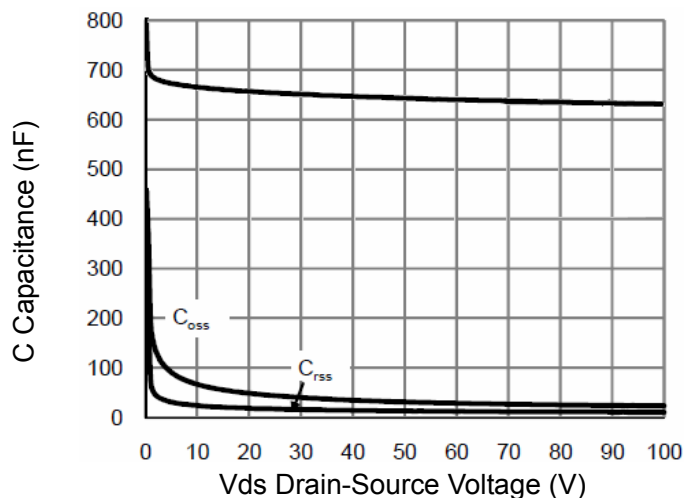


Figure 7 Capacitance vs Vds

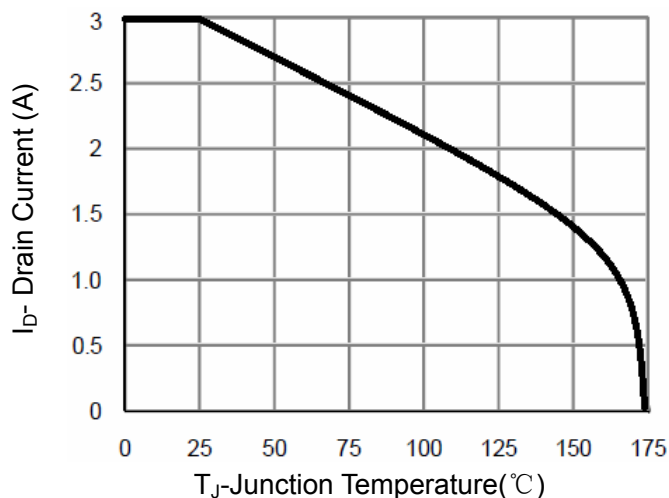


Figure 9 BV_{DSS} vs Junction Temperature

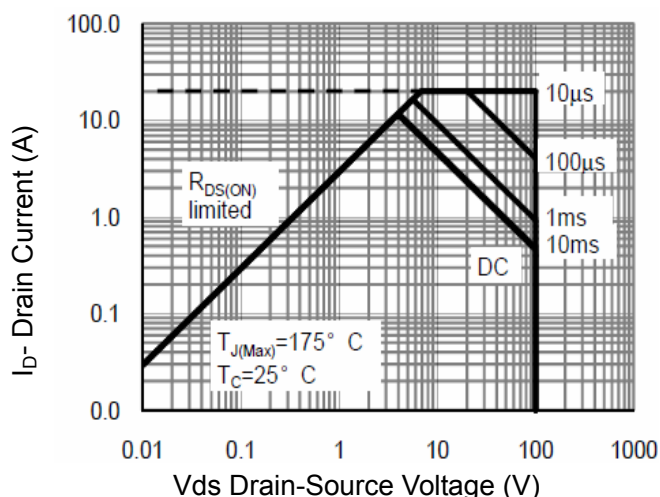


Figure 8 Safe Operation Area

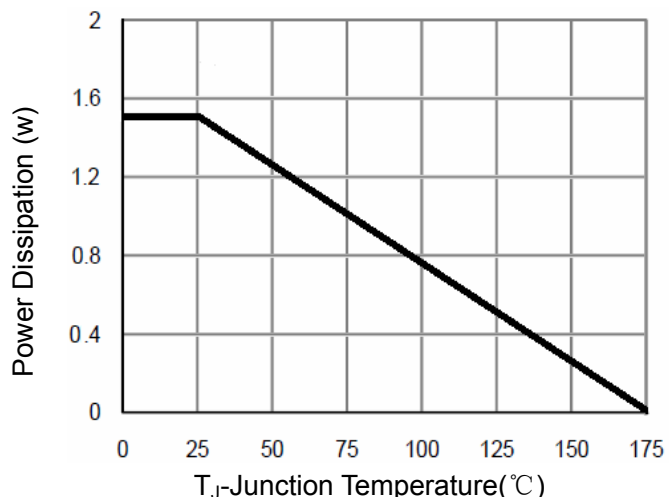


Figure 10 Power De-rating

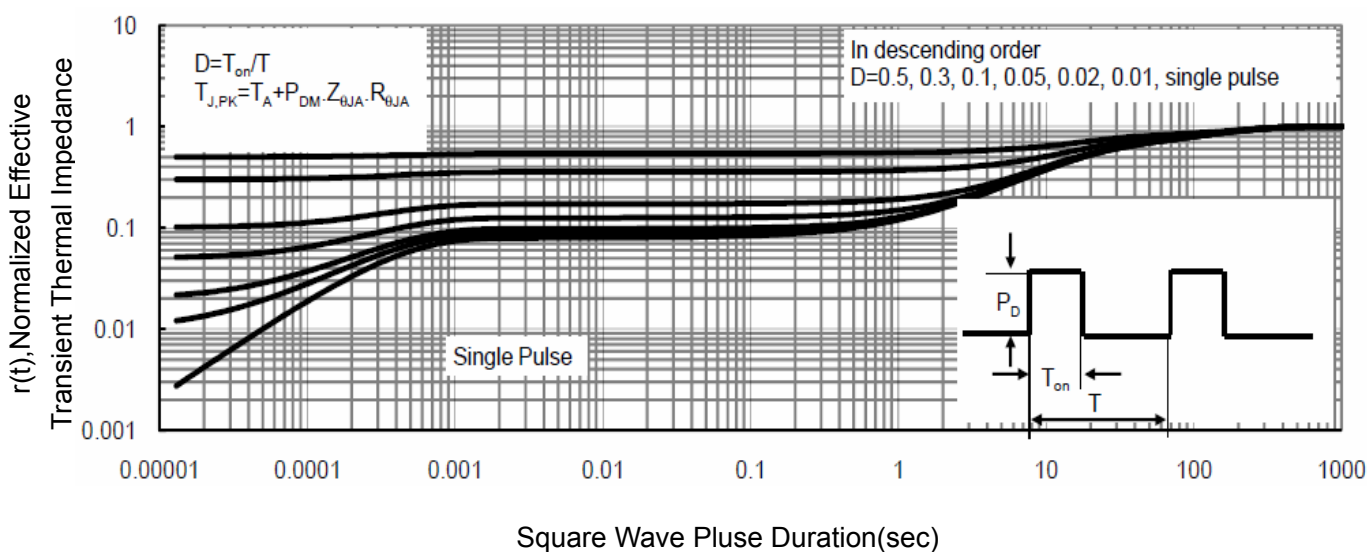
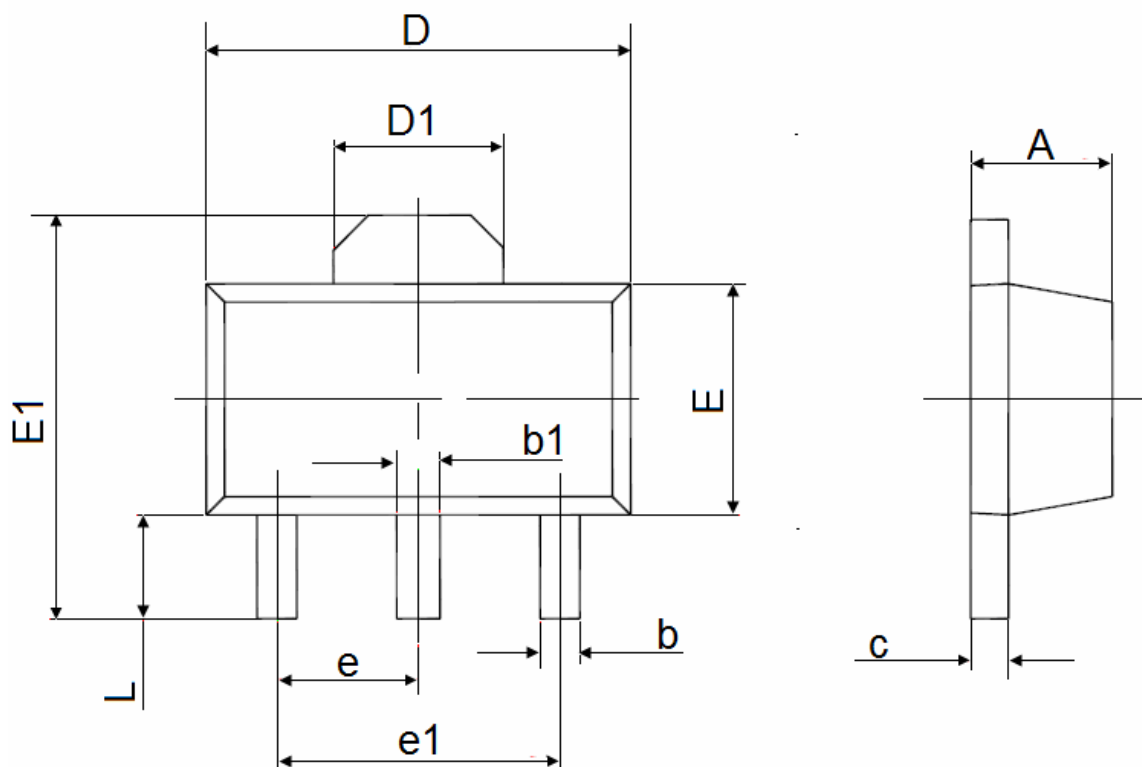


Figure 11 Normalized Maximum Transient Thermal Impedance

SOT-89-3L Package Information



| Symbol | Dimensions In Millimeters | | Dimensions In Inches | |
|--------|---------------------------|-------|----------------------|-------|
| | Min | Max | Min | Max |
| A | 1.400 | 1.600 | 0.055 | 0.063 |
| b | 0.320 | 0.520 | 0.013 | 0.020 |
| b1 | 0.400 | 0.580 | 0.016 | 0.023 |
| c | 0.350 | 0.440 | 0.014 | 0.017 |
| D | 4.400 | 4.600 | 0.173 | 0.181 |
| D1 | 1.550 REF. | | 0.061 REF. | |
| E | 2.300 | 2.600 | 0.091 | 0.102 |
| E1 | 3.940 | 4.250 | 0.155 | 0.167 |
| e | 1.500 TYP. | | 0.060 TYP. | |
| e1 | 3.000 TYP. | | 0.118 TYP. | |
| L | 0.900 | 1.200 | 0.035 | 0.047 |

Notes

1. All dimensions are in millimeters.
2. Tolerance $\pm 0.10\text{mm}$ (4 mil) unless otherwise specified
3. Package body sizes exclude mold flash and gate burrs. Mold flash at the non-lead sides should be less than 5 mils.
4. Dimension L is measured in gauge plane.
5. Controlling dimension is millimeter, converted inch dimensions are not necessarily exact.

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